

# RELIABILITY REPORT





**RELIABILITY DATA  
LTC1404  
8/21/2006**

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SOIC/SOT/MSOP	80	9813	9813	80.05	0
	80			80.05	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	50	9739	9739	1.20	0
	50			1.20	0

(1) Assumes Activation Energy = 0.7 Electron Volts  
 (2) Not Enough Data to Predict Failure Rate  
 (3) Refer to Rel Data Pack for Generic Product Family Data  
 Note: 1 FIT = 1 Failure in One Billion Hours.